FORM PTO-1449 (Rev. 4/92)

U.S. Department of Commerce Patent and Trademark Office

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

ATTY, DOCKET NO.	SERIAL NO.
503.30414V18	09/614 764
APPLICANT KATO, et al.	

GROUP

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U.S. PATENT DOCUMENTS

FILING DATE July 12, 2000

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EXAMINER INITÆAL			DOCL	MENT N	UMBER	_		DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
RYPSING	3	6	5	2	4	4	4	5 (2)-72	Lester, et al.			
SMS	3	9	8	1	7	9	1	9-76	Rosvold			
SMG	4	2	2	6	8	9	7	10-80	Coleman		_	•
sma	4	3	1	1	4	2	7	1-82	Coad, et al.			
Sala	4	3	1	3	8	1	5	2-82	Graves, Jr. et al.			
SWK	4	4	4	9	8	8	5	5-84	Hertel, et al.	_		
sm4	4	4	5	7	6	6	1	7-84	Flint, et al.	_	_	
Sanc	4	5	3	4	3	1	4	8-85	Ackley			
SMG	4	5	6	3	2	4	0	1-86	Shibata, et al.		_	
SWIL	4	6	3	4	3	3	1	1-87	Hertel	_	_	
Suc	4	7	0	5	9	5	1	11-87	Layman, et al.	_	_	

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				DOC	JMENT N	UMBER			DATE COUNTRY	CLASS	SUBCLASS	TRANSLATION		
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Smg		6	2	8	9	8	8	1	4-87	Japan			х	
SMG	6	2	2	0	7	8	6	6	9-87	Japan		<u> </u>	х	
SMG			1	3	1	9	7	0	2-89	Japan		_	х	<u></u>
Song			1	3	1	9	7	1	2-89	Japan		>	x	
Sanci			6	3	6	5	8	2	1-89	Japan			х	
Srus		1	1	3	5	O	1	5	5-89	Japan	_	-	x	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

SM9	R.P.H. Chang, "Multipurpose plasma reactor for materials research and processing", J. Vac. Sci. Technol., Vol. 14, No. 1, Jan./Feb. 1977, pages 278-280.
SMG	Semiconductor Equipment Association of Japan, "Terminological Dictionary of Semiconductor Equipment", front, table, page 183, back, November 20, 1987.
SML	Semiconductor Equipment Association of Japan, "Semiconductor News", Vol. 4, pp. 38-43, April 10, 1987 (w/translation)

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INITIAL			ĺ	DOCU	MENT NO		1		DATE	NAME	CLASS	SUBCLASS	IF APPROP	RIATE
SM4		4	7	1	5	7_	6	4	12-87	Hutchinson	<u> </u>			
SMC		4	8	5	1	1	0	1	7-89	Hutchinson				
SMG		4	8	3	6	7	3	3	6-89	Hertel, et al.				
Sarh		4	8	3	6	9	0	5	6-89	Davis, et al.				
Sinc		4	8	9	5	1	0	7	1-90	Yano, et al.		+-		
Sing		4	9	0	2	9	3	4	2-90	Miyamura, et al.		+		
Smg		4	9	0	3	9	3	7	2-90	Jakuniec, et al.				
SMC		4	9	0_	9	6	9	5	3-90	Hurwitt, et al.	-			
Sm4		4	9	1	1	5	9	7	3-90	Mäydan, et al.				
SW.		4	9	1	5	5	6	4	4-90	Eror, et al.	_			
SWh		4	9	1	7	5	5	6	4-90	Stark, et al.		<u> </u>		
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Sma			2	6	5	2	5	2	3-90	Japan	_		х	
SWE		6	4	1	2	0	3	7	1-89	Japan			х	ļ
Sma	:		2	6	1	0	6	4	3-90	Japan	<u> </u>			х
SING		1	3	1	0	5	5	3	12-89	Japan				x
SM4		1	2	5	1	7	3	4	10-89	Japan	-			х
SMG		6	2	4	4	5	7	1	2-87	Japan				×
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EXAMINER INITIAL			DOCL	IMENT N	UMBER			DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SMG	5	0	0	7	9	8	1	4-91	Kawasaki, et al.	_		
Sm4	5	2	9	2	3	9	3	3-94	Maydan, et al.	_	<u> </u>	
Sura	5	4	5	2	1	6	6	9-95	Aylwin, et al.			
SMG	5	5	0	4	0	3	3	4-96	Bajor, et al.	_		
SMG	5	5	0	4	3	4	7	4-96	Jovanovic, et al.			
SMG	5	5	5	6	7	1	4	9-96	Fukuyama, et al.	_		
SMG	5	6	5	1	8	5	8	7-97	Lin	_		
SINC	5	6	7	5	4	6	1	10-97	Aylwin, et al.	_		
SAL	4	3	1	3	7	8	3	2-82	Davies, et al.			
SMG	4	3	1	8	7	6	7	3-82	Hijikata, et al.	-		
SMG	4	9	6	9	7	9	0	11-90	Petz, et al.		_	

FOREIGN PATENT DOCUMENTS Abstract/ SUBCLASS TRANSLATION DOCUMENT NUMBER DATE COUNTRY CLASS SMG X 6 2 0 4 6 3 3-87 Japan Sma 2 3 7 X 1 0 6 0 4-90 **Japan** SMG Х 7 2 5 9 5 7 7 2-82 Japan SMG 7 3 5 3 2 0 6-88 X 6 1 **Japan**

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Steve Garine

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Surg	 	4	9	3	6	3	2	9	6-90	Giles, et al. Michael, et al.	134	902		
Sinh	<u> </u>	5	0	1	4	2	1	7	5-91	Savage	364	550		
_Sug		5	0	0	7	9	8	1	4-91	Kawasaki, et al.		_		
SMG		4	1	3	8	3	0	6	2-79	Niwa	156	345		
Since		4	5	7	6	6	9	8	3-86	Gallagher, et al.	204	192		
SMC		5	0	1	4	2	1	7	5-91	Savage	364	498		
5MG		5	3	5	1	4	1	5	10-94	Brooks, et al.	34	389		
Sinch		4	6	4	3	6	2	9	2-87	Takahashi, et al.	414	331		
SWA		4	8	2	4	3	0	9	4-89	Kakehi, et al.	414	217		
SAG		4	9	5	1	6	0	1	8-90	Maydan, et al.	414	217X		
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3mc	2	0	3	8	1	3	3	8	5-90	Europe			<u> </u>	
SEAG		6	4	1	2	0	3	7	1-89	Japan		7		
Sma		<u> </u>	4	3	0	5	4	9	4-92	Japan				ļ
SMG		8	7	0	7	3	0	9	5-87	PCT Int'l Appl.				
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SMS		5 5 0 9 7 7 1							4-96	Hiroki	414	217	
542 4		5	4	6	2	3	9	7	10-95	lwabuchi	414	222	
SMG		5	6	8	5	6	8	4	11-97	Kato, et al.	414	217	
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SMG	2	0	2	4	6	4	5	3	4-87	Europe				
SMG			2	6	5_	2	5	2	3-90	Japan				
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